Sheet 1 of 2

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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

Information Disclosure Statement by Applicant

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ATTY.	DOCKET	NO.
65304	-0161	

SERIAL NO. 09/779,149

APPLICANT

Hajduk et al.

FILING DATE

02/08/2001

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Sheet 2 of 2

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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 65304-0161

SERIAL NO. 09/779,149

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Information Disclosure Statement by Applicant

APPLICANT Hajduk et al.

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FILING DATE 02/08/2001

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Application Number	09/779,149	_					
Filing Date	02/08/2001						
First Named Inventor	Damian Hajduk						
Group Art Unit	2812						
Examiner Name							
Attorney Docket Number	1012-123D2	•					

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of 3

Application Number 09/779,149

Filing Date 02/08/2001

First Named Inventor Damian Hajduk

Group Art Unit 2812

Examiner Name

Attorney Docket Number 1012-123D2 (99-90DIV2)

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First Named Inventor Damian Hajduk

Group Art Unit 2812

Examiner Name

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First Named Inventor	Damian Hajduk					
Group Art Unit	2812					
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TRADEMARK

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Complete if Known 09/779,149 **Application Number** 02/08/2001 Filing Date Damian Hajduk **First Named Inventor** 2812 Group Art Unit **Examiner Name** Attorney Docket Number 1012-123D2 (99-90DIV2)

Examiner Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue nui publisher, city and/or country where published. U.S. Patent Application Serial No. 09/939,404 entitled "High Throughput Mecland Bulge Testing of Material Libraries," (D. Hajduk et al.) filed on August 24. U.S. Patent Application Serial No. 09/939,252 entitled "High Throughput M Serial Property Testing of Material Libraries," (P. Mansky) filed on August 24. U.S. Patent Application Serial No. 09/939,139 entitled "High Throughput Screening," (M. Kossuth et al.) filed on August 24, 2001. U.S. Patent Application Serial No. 09/939,149 entitled "High Throughput Testing Of Materials" (Paul Manksy et al.) filed on August 24, 2001. U.S. Patent Application Serial No. 09/939,263 entitled "High Throughput Meclasting of Materials Libraries Using Capacitance," (D. Hajduk et al.) filed on August 25. Patent Application Serial No. 09/938,994 entitled "High Throughput Meclasting of Materials Libraries Using a Piezoelectric," (D. Hajduk) filed on August 26. Design of Combinatorial Material Libraries" (Lacy, et al.) filed on October 1 U.S. Application Serial No. 09/578,997 entitled "High Throughput Viscor Method of Using Same" filed May 25, 2000	mber(s), hanical Property , 2001. lechanical Rapid	
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		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	$\frac{1}{2}$
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	
TA		U.S. Application Serial No. 09/420,334 entitled "Graphic Design of Combinatorial Material Libraries" (Lacy, et al.) filed on October 18, 1999	
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